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Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details

Product Status	Active
Number of LABs/CLBs	44280
Number of Logic Elements/Cells	566784
Total RAM Bits	33619968
Number of I/O	640
Number of Gates	-
Voltage - Supply	0.95V ~ 1.05V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 100°C (TJ)
Package / Case	1924-BBGA, FCBGA
Supplier Device Package	1924-FCBGA (45x45)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc6vhx565t-2ffg1924e

Table 4: Typical Quiescent Supply Current (Cont'd)

Symbol	Description	Device	Speed and Temperature Grade						Units
			-3 (C)	-2 (C, E, & I)	-1 (C & I)	-1 (I & M) ⁽²⁾	-1L (C)	-1L (I) ⁽¹⁾	
I_{CC0Q}	Quiescent V_{CC0} supply current	XC6VLX75T	1	1	1	N/A	1	1	mA
		XC6VLX130T	1	1	1	N/A	1	1	mA
		XC6VLX195T	1	1	1	N/A	1	1	mA
		XC6VLX240T	2	2	2	N/A	2	2	mA
		XC6VLX365T	2	2	2	N/A	2	2	mA
		XC6VLX550T ⁽³⁾	N/A	3	3	N/A	3	3	mA
		XC6VLX760 ⁽³⁾	N/A	3	3	N/A	3	3	mA
		XC6VSX315T	2	2	2	N/A	2	2	mA
		XC6VSX475T ⁽³⁾	N/A	2	2	N/A	2	2	mA
		XC6VHX250T	1	1	1	N/A	N/A	N/A	mA
		XC6VHX255T	1	1	1	N/A	N/A	N/A	mA
		XC6VHX380T ⁽⁴⁾	2	2	2	N/A	N/A	N/A	mA
		XC6VHX565T ⁽⁵⁾	N/A	2	2	N/A	N/A	N/A	mA
		XQ6VLX130T	N/A	1	N/A	1	N/A	1	mA
		XQ6VLX240T	N/A	2	N/A	2	N/A	2	mA
		XQ6VLX550T ⁽⁷⁾	N/A	N/A	N/A	3	N/A	3	mA
		XQ6VSX315T	N/A	2	N/A	2	N/A	2	mA
		XQ6VSX475T ⁽⁷⁾	N/A	N/A	N/A	2	N/A	2	mA

Power-On Power Supply Requirements

Xilinx FPGAs require a certain amount of supply current during power-on to insure proper device initialization. The actual current consumed depends on the power-on sequence and ramp rate of the power supply.

The recommended power-on sequence for Virtex-6 devices is V_{CCINT} , V_{CCAUX} , and V_{CCO} to meet the power-up current requirements listed in [Table 5](#). V_{CCINT} can be powered up or down at any time, but power up current specifications can vary from [Table 5](#). The device will have no physical damage or reliability concerns if V_{CCINT} , V_{CCAUX} , and V_{CCO} sequence cannot be followed.

If the recommended power-up sequence cannot be followed and the I/Os must remain 3-stated throughout configuration, then V_{CCAUX} must be powered prior to V_{CCO} or V_{CCAUX} and V_{CCO} must be powered by the same supply. Similarly, for power-down, the reverse V_{CCAUX} and V_{CCO} sequence is recommended if the I/Os are to remain 3-stated.

The GTH transceiver supplies must be powered using a MGTHAVCC, MGTHAVCCR, MGTHAVCCPLL, and MGTHAVTT sequence. There are no sequencing requirement for these supplies with respect to the other FPGA supply voltages. For more detail see [Table 27: GTH Transceiver Power Supply Sequencing](#). There are no sequencing requirements for the GTX transceivers power supplies.

[Table 5](#) shows the minimum current, in addition to I_{CCQ} , that are required by Virtex-6 devices for proper power-on and configuration. If the current minimums shown in [Table 4](#) and [Table 5](#) are met, the device powers on after all three supplies have passed through their power-on reset threshold voltages. The FPGA must be configured after applying V_{CCINT} , V_{CCAUX} , and V_{CCO} for the appropriate configuration banks. Once initialized and configured, use the XPE tools to estimate current drain on these supplies.

Table 5: Power-On Current for Virtex-6 Devices

Device	$I_{CCINTMIN}$	$I_{CCAUXMIN}$	I_{CCOMIN}	Units
	Typ ⁽¹⁾	Typ ⁽¹⁾	Typ ⁽¹⁾	
XC6VLX75T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 10$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XC6VLX130T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 10$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XC6VLX195T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XC6VLX240T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XC6VLX365T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XC6VLX550T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XC6VLX760	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XC6VSX315T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XC6VSX475T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 50$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XC6VHX250T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XC6VHX255T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XC6VHX380T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XC6VHX565T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XQ6VLX130T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 100$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XQ6VLX240T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 100$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XQ6VLX550T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 100$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XQ6VSX315T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 100$	$I_{CCOQ} + 40 \text{ mA per bank}$	mA
XQ6VSX475T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 100$	$I_{CCOQ} + 40 \text{ mA per bank}$	mA

Notes:

1. Typical values are specified at nominal voltage, 25°C.
2. Use the XPower Estimator (XPE) spreadsheet tool (download at <http://www.xilinx.com/power>) to calculate maximum power-on currents.

HT DC Specifications (HT_25)

Table 8: HT DC Specifications

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
V_{CCO}	Supply Voltage		2.38	2.5	2.63	V
V_{OD}	Differential Output Voltage for XC devices	$R_T = 100 \Omega$ across Q and \bar{Q} signals	480	600	885	mV
	Differential Output Voltage for XQ devices		480	600	930	mV
ΔV_{OD}	Change in V_{OD} Magnitude		-15	-	15	mV
V_{OCM}	Output Common Mode Voltage	$R_T = 100 \Omega$ across Q and \bar{Q} signals	440	600	760	mV
ΔV_{OCM}	Change in V_{OCM} Magnitude		-15	-	15	mV
V_{ID}	Input Differential Voltage		200	600	1000	mV
ΔV_{ID}	Change in V_{ID} Magnitude		-15	-	15	mV
V_{ICM}	Input Common Mode Voltage		440	600	780	mV
ΔV_{ICM}	Change in V_{ICM} Magnitude		-15	-	15	mV

LVDS DC Specifications (LVDS_25)

Table 9: LVDS DC Specifications

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
V_{CCO}	Supply Voltage		2.38	2.5	2.63	V
V_{OH}	Output High Voltage for Q and \bar{Q}	$R_T = 100 \Omega$ across Q and \bar{Q} signals	-	-	1.675	V
V_{OL}	Output Low Voltage for Q and \bar{Q}	$R_T = 100 \Omega$ across Q and \bar{Q} signals	0.825	-	-	V
V_{ODIFF}	Differential Output Voltage ($Q - \bar{Q}$), Q = High ($\bar{Q} - Q$), \bar{Q} = High	$R_T = 100 \Omega$ across Q and \bar{Q} signals	247	350	600	mV
V_{OCM}	Output Common-Mode Voltage for XC devices	$R_T = 100 \Omega$ across Q and \bar{Q} signals	1.075	1.250	1.425	V
	Output Common-Mode Voltage for XQ devices		1.000	1.250	1.425	V
V_{IDIFF}	Differential Input Voltage ($Q - \bar{Q}$), Q = High ($\bar{Q} - Q$), \bar{Q} = High		100	350	600	mV
V_{ICM}	Input Common-Mode Voltage		0.3	1.2	2.2	V

Extended LVDS DC Specifications (LVDSEXT_25)

Table 10: Extended LVDS DC Specifications

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
V_{CCO}	Supply Voltage		2.38	2.5	2.63	V
V_{OH}	Output High Voltage for Q and \bar{Q}	$R_T = 100 \Omega$ across Q and \bar{Q} signals	-	-	1.785	V
V_{OL}	Output Low Voltage for Q and \bar{Q}	$R_T = 100 \Omega$ across Q and \bar{Q} signals	0.715	-	-	V
V_{ODIFF}	Differential Output Voltage ($Q - \bar{Q}$), Q = High ($\bar{Q} - Q$), \bar{Q} = High for XC devices	$R_T = 100 \Omega$ across Q and \bar{Q} signals	350	-	840	mV
	Differential Output Voltage ($Q - \bar{Q}$), Q = High ($\bar{Q} - Q$), \bar{Q} = High for XQ devices		350	-	850	mV
V_{OCM}	Output Common-Mode Voltage for XC devices	$R_T = 100 \Omega$ across Q and \bar{Q} signals	1.075	1.250	1.425	V
	Output Common-Mode Voltage for XQ devices		1.000	1.250	1.425	V
V_{IDIFF}	Differential Input Voltage ($Q - \bar{Q}$), Q = High ($\bar{Q} - Q$), \bar{Q} = High	Common-mode input voltage = 1.25V	100	-	1000	mV
V_{ICM}	Input Common-Mode Voltage	Differential input voltage = ± 350 mV	0.3	1.2	2.2	V

Table 23: GTX Transceiver Transmitter Switching Characteristics

Symbol	Description	Condition	Min	Typ	Max	Units
F_{GTXTX}	Serial data rate range		0.480	—	F_{GTXMAX}	Gb/s
T_{RTX}	TX Rise time	20%–80%	—	120	—	ps
T_{FTX}	TX Fall time	80%–20%	—	120	—	ps
T_{LLSKEW}	TX lane-to-lane skew ⁽¹⁾		—	—	350	ps
$V_{TXOOBVDPDPP}$	Electrical idle amplitude		—	—	15	mV
$T_{TXOOBTTRANSITION}$	Electrical idle transition time		—	—	75	ns
$TJ_{6.5}$	Total Jitter ⁽²⁾⁽³⁾	6.5 Gb/s	—	—	0.33	UI
$DJ_{6.5}$	Deterministic Jitter ⁽²⁾⁽³⁾		—	—	0.17	UI
$TJ_{5.0}$	Total Jitter ⁽²⁾⁽³⁾	5.0 Gb/s	—	—	0.33	UI
$DJ_{5.0}$	Deterministic Jitter ⁽²⁾⁽³⁾		—	—	0.15	UI
$TJ_{4.25}$	Total Jitter ⁽²⁾⁽³⁾	4.25 Gb/s	—	—	0.33	UI
$DJ_{4.25}$	Deterministic Jitter ⁽²⁾⁽³⁾		—	—	0.14	UI
$TJ_{3.75}$	Total Jitter ⁽²⁾⁽³⁾	3.75 Gb/s	—	—	0.34	UI
$DJ_{3.75}$	Deterministic Jitter ⁽²⁾⁽³⁾		—	—	0.16	UI
$TJ_{3.125}$	Total Jitter ⁽²⁾⁽³⁾	3.125 Gb/s	—	—	0.2	UI
$DJ_{3.125}$	Deterministic Jitter ⁽²⁾⁽³⁾		—	—	0.1	UI
$TJ_{3.125L}$	Total Jitter ⁽²⁾⁽³⁾	3.125 Gb/s ⁽⁴⁾	—	—	0.35	UI
$DJ_{3.125L}$	Deterministic Jitter ⁽²⁾⁽³⁾		—	—	0.16	UI
$TJ_{2.5}$	Total Jitter ⁽²⁾⁽³⁾	2.5 Gb/s ⁽⁵⁾	—	—	0.20	UI
$DJ_{2.5}$	Deterministic Jitter ⁽²⁾⁽³⁾		—	—	0.08	UI
$TJ_{1.25}$	Total Jitter ⁽²⁾⁽³⁾	1.25 Gb/s ⁽⁶⁾	—	—	0.15	UI
$DJ_{1.25}$	Deterministic Jitter ⁽²⁾⁽³⁾		—	—	0.06	UI
TJ_{600}	Total Jitter ⁽²⁾⁽³⁾	600 Mb/s	—	—	0.1	UI
DJ_{600}	Deterministic Jitter ⁽²⁾⁽³⁾		—	—	0.03	UI
TJ_{480}	Total Jitter ⁽²⁾⁽³⁾	480 Mb/s	—	—	0.1	UI
DJ_{480}	Deterministic Jitter ⁽²⁾⁽³⁾		—	—	0.03	UI

Notes:

1. Using same REFCLK input with TXENPMAPHASEALIGN enabled for up to 12 consecutive transmitters (three fully populated GTX Quads).
2. Using PLL_DIVSEL_FB = 2, 20-bit internal data width. These values are NOT intended for protocol specific compliance determinations.
3. All jitter values are based on a bit-error ratio of 10^{-12} .
4. PLL frequency at 1.5625 GHz and OUTDIV = 1.
5. PLL frequency at 2.5 GHz and OUTDIV = 2.
6. PLL frequency at 2.5 GHz and OUTDIV = 4.

Table 35: GTH Transceiver User Clock Switching Characteristics (1)

Symbol	Description	Conditions	Speed Grade			Units
			-3	-2	-1	
F _{TXOUT}	TXUSERCLKOUT maximum frequency		350	350	323	MHz
F _{RXOUT}	RXUSERCLKOUT maximum frequency		350	350	323	MHz
F _{TXIN}	TXUSERCLKIN maximum frequency	16-bit data path	350	350	323	MHz
		20-bit data path	280	280	258	MHz
		32-bit data path	350	350	323	MHz
		40-bit data path	280	280	258	MHz
		64-bit data path	175	175	162	MHz
		80-bit data path	140	140	129	MHz
		64B/66B-bit data path	170	170	157	MHz
F _{RXIN}	RXUSERCLKIN maximum frequency	16-bit data path	350	350	323	MHz
		20-bit data path	280	280	258	MHz
		32-bit data path	350	350	323	MHz
		40-bit data path	280	280	258	MHz
		64-bit data path	175	175	162	MHz
		80-bit data path	140	140	129	MHz
		64B/66B-bit data path	170	170	157	MHz

Notes:

- Clocking must be implemented as described in [UG371: Virtex-6 FPGA GTH Transceivers User Guide](#).

Table 36: GTH Transceiver Transmitter Switching Characteristics

Symbol	Description	Condition	Min	Typ	Max	Units
T _{RTX}	TX Rise time	20%–80%	—	50 ⁽³⁾	—	ps
T _{FTX}	TX Fall time	80%–20%	—	50 ⁽³⁾	—	ps
T _{LLSKEW}	TX lane-to-lane skew	within one GTH Quad	—	—	300	ps
Transmitter Output Jitter⁽¹⁾⁽²⁾						
TJ _{11.18}	Total Jitter	11.181 Gb/s	—	—	0.280	UI
DJ _{11.18}	Deterministic Jitter		—	—	0.170	UI
TJ _{10.3125}	Total Jitter	10.3125 Gb/s	—	—	0.280	UI
DJ _{10.3125}	Deterministic Jitter		—	—	0.170	UI
TJ _{9.953}	Total Jitter	9.953 Gb/s	—	—	0.280	UI
DJ _{9.953}	Deterministic Jitter		—	—	0.170	UI
TJ _{2.667}	Total Jitter	2.667 Gb/s	—	—	0.110	UI
DJ _{2.667}	Deterministic Jitter		—	—	0.060	UI
TJ _{2.488}	Total Jitter	2.488 Gb/s	—	—	0.110	UI
DJ _{2.488}	Deterministic Jitter		—	—	0.060	UI

Notes:

- These values are NOT intended for protocol specific compliance determinations.
- All jitter values are based on a bit-error ratio of $1e^{-12}$.
- Rise and fall times are specified at the transmitter package balls.

Integrated Interface Block for PCI Express Designs Switching Characteristics

More information and documentation on solutions for PCI Express designs can be found at:
<http://www.xilinx.com/technology/protocols/pciexpress.htm>

Table 39: Maximum Performance for PCI Express Designs

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
F _{PIPECLK}	Pipe clock maximum frequency	250	250	250	250	MHz
F _{USERCLK}	User clock maximum frequency	500	500	250	250	MHz
F _{DRPCLK}	DRP clock maximum frequency	250	250	250	250	MHz

System Monitor Analog-to-Digital Converter Specification

Table 40: Analog-to-Digital Specifications

Parameter	Symbol	Comments/Conditions	Min	Typ	Max	Units
$AV_{DD} = 2.5V \pm 5\%$, $V_{REFP} = 1.25V$, $V_{REFN} = 0V$, ADCCLK = 5.2 MHz, $T_j = -55^{\circ}C$ to $125^{\circ}C$ M-Grade, Typical values at $T_j=+35^{\circ}C$						
DC Accuracy: All external input channels. Both unipolar and bipolar modes.						
Resolution			10	–	–	Bits
Integral Nonlinearity	INL		–	–	± 1	LSBs
Differential Nonlinearity	DNL	No missing codes (T_{MIN} to T_{MAX}) Guaranteed Monotonic	–	–	± 0.9	LSBs
Unipolar Offset Error ⁽¹⁾		Uncalibrated	–	± 2	± 30	LSBs
Bipolar Offset Error ⁽¹⁾		Uncalibrated measured in bipolar mode	–	± 2	± 30	LSBs
Gain Error		Uncalibrated - External Reference	–	± 0.2	± 2	%
		Uncalibrated - Internal Reference	–	± 2	–	%
Bipolar Gain Error ⁽¹⁾		Uncalibrated - External Reference	–	± 0.2	± 2	%
		Uncalibrated - Internal Reference	–	± 2	–	%
Total Unadjusted Error (Uncalibrated)	TUE	Deviation from ideal transfer function. External 1.25V reference	–	± 10	–	LSBs
		Deviation from ideal transfer function. Internal reference	–	± 20	–	LSBs
Total Unadjusted Error (Calibrated)	TUE	Deviation from ideal transfer function. External 1.25V reference	–	± 1	± 2	LSBs
Calibrated Gain Temperature Coefficient		Variation of FS code with temperature	–	± 0.01	–	LSB/ $^{\circ}C$
DC Common-Mode Reject	CMRR _{DC}	$V_N = V_{CM} = 0.5V \pm 0.5V$, $V_P - V_N = 100mV$	–	70	–	dB
Conversion Rate⁽²⁾						
Conversion Time - Continuous	t _{CONV}	Number of CLK cycles	26	–	32	
Conversion Time - Event	t _{CONV}	Number of CLK cycles	–	–	21	
T/H Acquisition Time	t _{Acq}	Number of CLK cycles	4	–	–	
DRP Clock Frequency	DCLK	DRP clock frequency	8	–	80	MHz
ADC Clock Frequency	ADCCLK	Derived from DCLK	1	–	5.2	MHz
CLK Duty cycle			40	–	60	%

Performance Characteristics

This section provides the performance characteristics of some common functions and designs implemented in Virtex-6 devices. The numbers reported here are worst-case values; they have all been fully characterized. These values are subject to the same guidelines as the [Switching Characteristics, page 26](#).

Table 41: Interface Performances

Description	Speed Grade			
	-3	-2	-1	-1L
Networking Applications				
SDR LVDS transmitter (using OSERDES; DATA_WIDTH = 4 to 8)	710 Mb/s	710 Mb/s	650 Mb/s	585 Mb/s
DDR LVDS transmitter (using OSERDES; DATA_WIDTH = 4 to 10)	1.4 Gb/s	1.3 Gb/s	1.25 Gb/s	1.1 Gb/s
SDR LVDS receiver (SFI-4.1) ⁽¹⁾	710 Mb/s	710 Mb/s	650 Mb/s	585 Mb/s
DDR LVDS receiver (SPI-4.2) ⁽¹⁾	1.4 Gb/s	1.3 Gb/s	1.1 Gb/s	0.9 Gb/s
Maximum Physical Interface (PHY) Rate for Memory Interfaces⁽²⁾⁽³⁾⁽⁴⁾				
DDR2	800 Mb/s	800 Mb/s	800 Mb/s	606 Mb/s
DDR3	1066 Mb/s	1066 Mb/s	800 Mb/s	800 Mb/s
QDR II + SRAM	400 MHz	350 MHz	300 MHz	–
RLDRAM II	500 MHz	400 MHz	350 MHz	–

Notes:

1. LVDS receivers are typically bounded with certain applications where specific DPA algorithms dominate deterministic performance.
2. Verified on Xilinx memory characterization platforms designed according to the guidelines in UG: *Virtex-6 FPGA Memory Interface Solutions User Guide*.
3. Consult [DS186: Virtex-6 FPGA Memory Interface Solutions Data Sheet](#) for performance and feature information on memory interface cores (controller plus PHY).
4. Memory Interface data rates have not been tested over the junction temperature operating range for military (M) temperature devices. Customers are responsible for specifying and testing their specific M temperature grade memory implementation.

Switching Characteristics

All values represented in this data sheet are based on these speed specifications: v1.17 for -3, -2, and -1; and v1.10 for -1L. Switching characteristics are specified on a per-speed-grade basis and can be designated as Advance, Preliminary, or Production. Each designation is defined as follows:

Advance

These specifications are based on simulations only and are typically available soon after device design specifications are frozen. Although speed grades with this designation are considered relatively stable and conservative, some under-reporting might still occur.

Preliminary

These specifications are based on complete ES (engineering sample) silicon characterization. Devices and speed grades with this designation are intended to give a better indication of the expected performance of production silicon. The probability of under-reporting delays is greatly reduced as compared to Advance data.

Production

These specifications are released once enough production silicon of a particular device family member has been characterized to provide full correlation between specifications and devices over numerous production lots. There is no under-reporting of delays, and customers receive formal notification of any subsequent changes. Typically, the slowest speed grades transition to Production before faster speed grades.

All specifications are always representative of worst-case supply voltage and junction temperature conditions.

Since individual family members are produced at different times, the migration from one category to another depends completely on the status of the fabrication process for each device.

[Table 42](#) correlates the current status of each Virtex-6 device on a per speed grade basis.

Table 42: Virtex-6 Device Speed Grade Designations

Device	Speed Grade Designations		
	Advance	Preliminary	Production
XC6VLX75T			-3, -2, -1, -1L
XC6VLX130T			-3, -2, -1, -1L
XC6VLX195T			-3, -2, -1, -1L
XC6VLX240T			-3, -2, -1, -1L
XC6VLX365T			-3, -2, -1, -1L
XC6VLX550T			-2, -1, -1L
XC6VLX760			-2, -1, -1L
XC6VSX315T			-3, -2, -1, -1L
XC6VSX475T			-2, -1, -1L
XC6VHX250T			-3, -2, -1
XC6VHX255T			-3, -2, -1
XC6VHX380T			-3, -2, -1
XC6VHX565T			-2, -1
XQ6VLX130T			-2, -1, -1L
XQ6VLX240T			-2, -1, -1L
XQ6VLX550T			-1, -1L
XQ6VSX315T			-2, -1, -1L
XQ6VSX475T			-1, -1L

Testing of Switching Characteristics

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values.

For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer and back-annotate to the simulation net list. Unless otherwise noted, values apply to all Virtex-6 devices.

Table 44: IOB Switching Characteristics for the Commercial (XC) Virtex-6 Devices (Cont'd)

I/O Standard	T _{IOP1}				T _{IOP2}				T _{IOTP}				Units	
	Speed Grade				Speed Grade				Speed Grade					
	-3	-2	-1	-1L	-3	-2	-1	-1L	-3	-2	-1	-1L		
LVDCI_DV2_25	0.51	0.57	0.66	0.70	1.71	1.83	2.01	2.00	1.71	1.83	2.01	2.00	ns	
LVDCI_DV2_18	0.55	0.61	0.71	0.73	1.69	1.81	2.00	1.98	1.69	1.81	2.00	1.98	ns	
LVDCI_DV2_15	0.64	0.73	0.85	0.85	1.68	1.77	1.91	1.98	1.68	1.77	1.91	1.98	ns	
LVPECL_25	0.85	0.94	1.09	1.08	1.38	1.49	1.65	1.64	1.38	1.49	1.65	1.64	ns	
HSTL_I_12	0.81	0.91	1.06	1.06	1.48	1.60	1.78	1.74	1.48	1.60	1.78	1.74	ns	
HSTL_I_DCI	0.81	0.91	1.06	1.06	1.40	1.50	1.66	1.64	1.40	1.50	1.66	1.64	ns	
HSTL_II_DCI	0.81	0.91	1.06	1.06	1.37	1.49	1.68	1.66	1.37	1.49	1.68	1.66	ns	
HSTL_II_T_DCI	0.81	0.91	1.06	1.06	1.40	1.50	1.66	1.64	1.40	1.50	1.66	1.64	ns	
HSTL_III_DCI	0.81	0.91	1.06	1.06	1.34	1.45	1.62	1.61	1.34	1.45	1.62	1.61	ns	
HSTL_I_DCI_18	0.81	0.91	1.06	1.06	1.42	1.53	1.68	1.66	1.42	1.53	1.68	1.66	ns	
HSTL_II_T_DCI_18	0.81	0.91	1.06	1.06	1.36	1.46	1.62	1.59	1.36	1.46	1.62	1.59	ns	
HSTL_II_T_DCI_18	0.81	0.91	1.06	1.06	1.42	1.53	1.68	1.66	1.42	1.53	1.68	1.66	ns	
HSTL_III_DCI_18	0.81	0.91	1.06	1.06	1.43	1.54	1.69	1.67	1.43	1.54	1.69	1.67	ns	
DIFF_HSTL_I_18	0.85	0.94	1.09	1.08	1.47	1.58	1.75	1.72	1.47	1.58	1.75	1.72	ns	
DIFF_HSTL_I_DCI_18	0.85	0.94	1.09	1.08	1.42	1.53	1.68	1.66	1.42	1.53	1.68	1.66	ns	
DIFF_HSTL_I	0.85	0.94	1.09	1.08	1.45	1.56	1.73	1.71	1.45	1.56	1.73	1.71	ns	
DIFF_HSTL_I_DCI	0.85	0.94	1.09	1.08	1.40	1.50	1.66	1.64	1.40	1.50	1.66	1.64	ns	
DIFF_HSTL_II_18	0.85	0.94	1.09	1.08	1.50	1.62	1.81	1.78	1.50	1.62	1.81	1.78	ns	
DIFF_HSTL_II_DCI_18	0.85	0.94	1.09	1.08	1.36	1.46	1.62	1.59	1.36	1.46	1.62	1.59	ns	
DIFF_HSTL_II_T_DCI_18	0.85	0.94	1.09	1.08	1.42	1.53	1.68	1.66	1.42	1.53	1.68	1.66	ns	
DIFF_HSTL_II	0.85	0.94	1.09	1.08	1.44	1.56	1.74	1.72	1.44	1.56	1.74	1.72	ns	
DIFF_HSTL_II_DCI	0.85	0.94	1.09	1.08	1.37	1.49	1.68	1.66	1.37	1.49	1.68	1.66	ns	
SSTL2_I_DCI	0.81	0.91	1.06	1.06	1.42	1.53	1.70	1.68	1.42	1.53	1.70	1.68	ns	
SSTL2_II_DCI	0.81	0.91	1.06	1.06	1.39	1.50	1.67	1.69	1.39	1.50	1.67	1.69	ns	
SSTL2_II_T_DCI	0.81	0.91	1.06	1.06	1.42	1.53	1.70	1.68	1.42	1.53	1.70	1.68	ns	
SSTL18_I	0.81	0.91	1.06	1.06	1.47	1.58	1.75	1.73	1.47	1.58	1.75	1.73	ns	
SSTL18_II	0.81	0.91	1.06	1.06	1.39	1.50	1.67	1.66	1.39	1.50	1.67	1.66	ns	
SSTL18_I_DCI	0.81	0.91	1.06	1.06	1.40	1.51	1.67	1.65	1.40	1.51	1.67	1.65	ns	
SSTL18_II_DCI	0.81	0.91	1.06	1.06	1.36	1.47	1.63	1.62	1.36	1.47	1.63	1.62	ns	
SSTL18_II_T_DCI	0.81	0.91	1.06	1.06	1.40	1.51	1.67	1.65	1.40	1.51	1.67	1.65	ns	
SSTL15_T_DCI	0.81	0.91	1.06	1.06	1.41	1.52	1.68	1.66	1.41	1.52	1.68	1.66	ns	
SSTL15_DCI	0.81	0.91	1.06	1.06	1.41	1.52	1.68	1.66	1.41	1.52	1.68	1.66	ns	
DIFF_SSTL2_I	0.85	0.94	1.09	1.08	1.49	1.60	1.77	1.74	1.49	1.60	1.77	1.74	ns	
DIFF_SSTL2_I_DCI	0.85	0.94	1.09	1.08	1.42	1.53	1.70	1.68	1.42	1.53	1.70	1.68	ns	
DIFF_SSTL2_II	0.85	0.94	1.09	1.08	1.42	1.54	1.72	1.71	1.42	1.54	1.72	1.71	ns	
DIFF_SSTL2_II_DCI	0.85	0.94	1.09	1.08	1.39	1.50	1.67	1.69	1.39	1.50	1.67	1.69	ns	
DIFF_SSTL2_II_T_DCI	0.85	0.94	1.09	1.08	1.42	1.53	1.70	1.68	1.42	1.53	1.70	1.68	ns	

Table 44: IOB Switching Characteristics for the Commercial (XC) Virtex-6 Devices (Cont'd)

I/O Standard	T _{IOPI}				T _{IOOP}				T _{IOTP}				Units	
	Speed Grade				Speed Grade				Speed Grade					
	-3	-2	-1	-1L	-3	-2	-1	-1L	-3	-2	-1	-1L		
DIFF_SSTL18_I	0.85	0.94	1.09	1.08	1.47	1.58	1.75	1.73	1.47	1.58	1.75	1.73	ns	
DIFF_SSTL18_I_DCI	0.85	0.94	1.09	1.08	1.40	1.51	1.67	1.65	1.40	1.51	1.67	1.65	ns	
DIFF_SSTL18_II	0.85	0.94	1.09	1.08	1.39	1.50	1.67	1.66	1.39	1.50	1.67	1.66	ns	
DIFF_SSTL18_II_DCI	0.85	0.94	1.09	1.08	1.36	1.47	1.63	1.62	1.36	1.47	1.63	1.62	ns	
DIFF_SSTL18_II_T_DCI	0.85	0.94	1.09	1.08	1.40	1.51	1.67	1.65	1.40	1.51	1.67	1.65	ns	
DIFF_SSTL15	0.81	0.91	1.06	1.06	1.42	1.54	1.71	1.69	1.42	1.54	1.71	1.69	ns	
DIFF_SSTL15_DCI	0.81	0.91	1.06	1.06	1.41	1.52	1.68	1.66	1.41	1.52	1.68	1.66	ns	
DIFF_SSTL15_T_DCI	0.81	0.91	1.06	1.06	1.41	1.52	1.68	1.66	1.41	1.52	1.68	1.66	ns	

Table 45: IOB Switching Characteristics for the Defense-grade (XQ) Virtex-6 Devices

I/O Standard	T _{IOPI}			T _{IOOP}			T _{IOTP}			Units	
	Speed Grade			Speed Grade			Speed Grade				
	-2	-1	-1L	-2	-1	-1L	-2	-1	-1L		
LVDS_25	0.94	1.09	1.08	1.54	2.16	1.62	1.54	2.16	1.62	ns	
LVDSEXT_25	0.94	1.09	1.08	1.65	2.20	1.73	1.65	2.20	1.73	ns	
HT_25	0.94	1.09	1.08	1.62	2.20	1.69	1.62	2.20	1.69	ns	
BLVDS_25	0.94	1.09	1.08	1.50	3.18	1.65	1.50	3.18	1.65	ns	
RSDS_25 (point to point)	0.94	1.09	1.08	1.54	2.22	1.62	1.54	2.22	1.62	ns	
HSTL_I	0.91	1.06	1.06	1.56	2.44	1.71	1.56	2.44	1.71	ns	
HSTL_II	0.91	1.06	1.06	1.56	2.21	1.72	1.56	2.21	1.72	ns	
HSTL_III	0.91	1.06	1.06	1.54	2.50	1.69	1.54	2.50	1.69	ns	
HSTL_I_18	0.91	1.06	1.06	1.58	2.43	1.72	1.58	2.43	1.72	ns	
HSTL_II_18	0.91	1.06	1.06	1.62	2.30	1.78	1.62	2.30	1.78	ns	
HSTL_III_18	0.91	1.06	1.06	1.54	2.49	1.69	1.54	2.49	1.69	ns	
SSTL2_I	0.91	1.06	1.06	1.60	2.50	1.74	1.60	2.50	1.74	ns	
SSTL2_II	0.91	1.06	1.06	1.54	2.49	1.71	1.54	2.49	1.71	ns	
SSTL15	0.91	1.06	1.06	1.54	2.07	1.69	1.54	2.07	1.69	ns	
LVCMOS25, Slow, 2 mA	0.57	0.66	0.70	5.46	6.01	5.63	5.46	6.01	5.63	ns	
LVCMOS25, Slow, 4 mA	0.57	0.66	0.70	3.49	3.79	3.65	3.49	3.79	3.65	ns	
LVCMOS25, Slow, 6 mA	0.57	0.66	0.70	2.81	3.08	2.95	2.81	3.08	2.95	ns	
LVCMOS25, Slow, 8 mA	0.57	0.66	0.70	2.41	2.72	2.59	2.41	2.72	2.59	ns	
LVCMOS25, Slow, 12 mA	0.57	0.66	0.70	1.95	2.23	2.10	1.95	2.23	2.10	ns	
LVCMOS25, Slow, 16 mA	0.57	0.66	0.70	2.05	2.29	2.21	2.05	2.29	2.21	ns	
LVCMOS25, Slow, 24 mA	0.57	0.66	0.70	1.82	2.24	1.98	1.82	2.24	1.98	ns	
LVCMOS25, Fast, 2 mA	0.57	0.66	0.70	5.49	6.04	5.62	5.49	6.04	5.62	ns	
LVCMOS25, Fast, 4 mA	0.57	0.66	0.70	3.50	3.82	3.65	3.50	3.82	3.65	ns	
LVCMOS25, Fast, 6 mA	0.57	0.66	0.70	2.73	2.99	2.88	2.73	2.99	2.88	ns	
LVCMOS25, Fast, 8 mA	0.57	0.66	0.70	2.33	2.65	2.53	2.33	2.65	2.53	ns	
LVCMOS25, Fast, 12 mA	0.57	0.66	0.70	1.88	2.08	2.03	1.88	2.08	2.03	ns	

Table 45: IOB Switching Characteristics for the Defense-grade (XQ) Virtex-6 Devices (Cont'd)

I/O Standard	T _{IOPI}			T _{IOOP}			T _{IOTP}			Units	
	Speed Grade			Speed Grade			Speed Grade				
	-2	-1	-1L	-2	-1	-1L	-2	-1	-1L		
LVCMOS25, Fast, 16 mA	0.57	0.66	0.70	1.92	2.15	2.08	1.92	2.15	2.08	ns	
LVCMOS25, Fast, 24 mA	0.57	0.66	0.70	1.79	2.15	1.96	1.79	2.15	1.96	ns	
LVCMOS18, Slow, 2 mA	0.61	0.71	0.73	4.47	4.87	4.30	4.47	4.87	4.30	ns	
LVCMOS18, Slow, 4 mA	0.61	0.71	0.73	2.96	3.21	2.94	2.96	3.21	2.94	ns	
LVCMOS18, Slow, 6 mA	0.61	0.71	0.73	2.43	2.64	2.47	2.43	2.64	2.47	ns	
LVCMOS18, Slow, 8 mA	0.61	0.71	0.73	2.11	2.41	2.24	2.11	2.41	2.24	ns	
LVCMOS18, Slow, 12 mA	0.61	0.71	0.73	1.99	2.30	2.10	1.99	2.30	2.10	ns	
LVCMOS18, Slow, 16 mA	0.61	0.71	0.73	1.95	2.30	2.04	1.95	2.30	2.04	ns	
LVCMOS18, Fast, 2 mA	0.61	0.71	0.73	4.23	4.57	4.08	4.23	4.57	4.08	ns	
LVCMOS18, Fast, 4 mA	0.61	0.71	0.73	2.76	2.97	2.74	2.76	2.97	2.74	ns	
LVCMOS18, Fast, 6 mA	0.61	0.71	0.73	2.28	2.46	2.32	2.28	2.46	2.32	ns	
LVCMOS18, Fast, 8 mA	0.61	0.71	0.73	1.99	2.34	2.14	1.99	2.34	2.14	ns	
LVCMOS18, Fast, 12 mA	0.61	0.71	0.73	1.80	2.19	1.88	1.80	2.19	1.88	ns	
LVCMOS18, Fast, 16 mA	0.61	0.71	0.73	1.74	2.18	1.88	1.74	2.18	1.88	ns	
LVCMOS15, Slow, 2 mA	0.73	0.85	0.85	3.77	4.29	3.91	3.77	4.29	3.91	ns	
LVCMOS15, Slow, 4 mA	0.73	0.85	0.85	2.79	3.10	2.93	2.79	3.10	2.93	ns	
LVCMOS15, Slow, 6 mA	0.73	0.85	0.85	2.32	2.68	2.50	2.32	2.68	2.50	ns	
LVCMOS15, Slow, 8 mA	0.73	0.85	0.85	1.98	2.29	2.24	1.98	2.29	2.24	ns	
LVCMOS15, Slow, 12 mA	0.73	0.85	0.85	1.91	2.23	2.07	1.91	2.23	2.07	ns	
LVCMOS15, Slow, 16 mA	0.73	0.85	0.85	1.83	2.23	1.98	1.83	2.23	1.98	ns	
LVCMOS15, Fast, 2 mA	0.73	0.85	0.85	3.77	4.28	3.91	3.77	4.28	3.91	ns	
LVCMOS15, Fast, 4 mA	0.73	0.85	0.85	2.53	2.78	2.66	2.53	2.78	2.66	ns	
LVCMOS15, Fast, 6 mA	0.73	0.85	0.85	2.05	2.42	2.16	2.05	2.42	2.16	ns	
LVCMOS15, Fast, 8 mA	0.73	0.85	0.85	1.90	2.20	2.04	1.90	2.20	2.04	ns	
LVCMOS15, Fast, 12 mA	0.73	0.85	0.85	1.77	2.11	1.90	1.77	2.11	1.90	ns	
LVCMOS15, Fast, 16 mA	0.73	0.85	0.85	1.76	2.11	1.92	1.76	2.11	1.92	ns	
LVCMOS12, Slow, 2 mA	0.81	0.93	0.95	3.39	3.75	3.54	3.39	3.75	3.54	ns	
LVCMOS12, Slow, 4 mA	0.81	0.93	0.95	2.63	2.93	2.79	2.63	2.93	2.79	ns	
LVCMOS12, Slow, 6 mA	0.81	0.93	0.95	2.11	2.67	2.26	2.11	2.67	2.26	ns	
LVCMOS12, Slow, 8 mA	0.81	0.93	0.95	2.02	2.25	2.17	2.02	2.25	2.17	ns	
LVCMOS12, Fast, 2 mA	0.81	0.93	0.95	2.98	3.39	3.11	2.98	3.39	3.11	ns	
LVCMOS12, Fast, 4 mA	0.81	0.93	0.95	2.16	2.70	2.31	2.16	2.70	2.31	ns	
LVCMOS12, Fast, 6 mA	0.81	0.93	0.95	1.89	2.34	2.05	1.89	2.34	2.05	ns	
LVCMOS12, Fast, 8 mA	0.81	0.93	0.95	1.82	2.10	1.98	1.82	2.10	1.98	ns	
LVDCI_25	0.57	0.70	0.70	2.14	2.82	2.26	2.14	2.82	2.26	ns	
LVDCI_18	0.61	0.71	0.73	2.23	2.78	2.38	2.23	2.78	2.38	ns	
LVDCI_15	0.73	0.85	0.85	2.01	2.75	2.18	2.01	2.75	2.18	ns	
LVDCI_DV2_25	0.57	0.70	0.70	1.83	2.37	2.00	1.83	2.37	2.00	ns	

Table 50: OLOGIC Switching Characteristics

Symbol	Description	Speed Grade					Units
		-3	-2	-1 (XC)	-1 (XQ)	-1L	
Setup/Hold							
T _{DCK/T_OCKD}	D1/D2 pins Setup/Hold with respect to CLK	0.45/ -0.08	0.50/ -0.08	0.54/ -0.08	0.54/ -0.08	0.69/ -0.11	ns
T _O OCECK/T _O CKOCE	OCE pin Setup/Hold with respect to CLK	0.17/ -0.03	0.20/ -0.03	0.22/ -0.03	0.27/ -0.05	0.27/ -0.04	ns
T _S SRCK/T _O CKSR	SR pin Setup/Hold with respect to CLK	0.59/ -0.24	0.62/ -0.24	0.54/ -0.08	0.54/ -0.08	0.79/ -0.35	ns
T _T TCK/T _O CKT	T1/T2 pins Setup/Hold with respect to CLK	0.44/ -0.07	0.51/ -0.07	0.56/ -0.07	0.60/ -0.10	0.68/ -0.13	ns
T _T TCECK/T _O CKTCE	TCE pin Setup/Hold with respect to CLK	0.15/ -0.04	0.19/ -0.04	0.21/ -0.04	0.27/ -0.05	0.29/ -0.05	ns
Combinatorial							
T _D OQ	D1 to OQ out or T1 to TQ out	0.78	0.87	1.01	1.01	1.15	ns
Sequential Delays							
T _O CKQ	CLK to OQ/TQ out	0.54	0.61	0.71	0.71	0.80	ns
T _R Q	SR pin to OQ/TQ out	0.80	0.90	1.05	1.05	1.19	ns
T _G SRQ	Global Set/Reset to Q outputs	7.60	7.60	10.51	10.51	10.51	ns
Set/Reset							
T _R PW	Minimum Pulse Width, SR inputs	0.78	0.95	1.20	1.20	1.30	ns, Min

Table 62: Regional Clock Switching Characteristics (BUFR) (Cont'd)

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
T _{BRDO_O}	Propagation delay from CLR to O	0.69	0.74	0.80	1.12	ns
Maximum Frequency						
F _{MAX} ⁽¹⁾	Regional clock tree (BUFR)	500	420	300	300	MHz

Notes:

1. The maximum input frequency to the BUFR is the BUFIN F_{MAX} frequency.

Table 63: Horizontal Clock Buffer Switching Characteristics (BUFH)

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
T _{BHCKO_O}	BUFH delay from I to O	0.10	0.11	0.13	0.15	ns
T _{BHCKC_CE} /T _{BHCKC_CE}	CE pin Setup and Hold	0.04/ 0.04	0.04/ 0.04	0.05/ 0.05	0.04/ 0.04	ns
Maximum Frequency						
F _{MAX}	Horizontal clock buffer (BUFH)	800	750	700	667	MHz

MMCM Switching Characteristics

Table 64: MMCM Specification

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
F _{INMAX}	Maximum Input Clock Frequency ⁽¹⁾	800	750	700	700	MHz
F _{INMIN}	Minimum Input Clock Frequency	10	10	10	10	MHz
F _{INJITTER}	Maximum Input Clock Period Jitter	< 20% of clock input period or 1 ns Max				
F _{INDUTY} ⁽²⁾	Allowable Input Duty Cycle: 10—49 MHz	25/75				%
	Allowable Input Duty Cycle: 50—199 MHz	30/70				%
	Allowable Input Duty Cycle: 200—399 MHz	35/65				%
	Allowable Input Duty Cycle: 400—499 MHz	40/60				%
	Allowable Input Duty Cycle: >500 MHz	45/55				%
F _{MIN_PSCLK}	Minimum Dynamic Phase Shift Clock Frequency	0.01	0.01	0.01	0.01	MHz
F _{MAX_PSCLK}	Maximum Dynamic Phase Shift Clock Frequency	550	500	450	450	MHz
F _{VCOMIN}	Minimum MMCM VCO Frequency	600	600	600	600	MHz
F _{VCOMAX}	Maximum MMCM VCO Frequency	1600	1440	1200	1200	MHz
F _{BANDWIDTH}	Low MMCM Bandwidth at Typical ⁽³⁾	1.00	1.00	1.00	1.00	MHz
	High MMCM Bandwidth at Typical ⁽³⁾	4.00	4.00	4.00	4.00	MHz
T _{STATPHAOFFSET}	Static Phase Offset of the MMCM Outputs ⁽⁴⁾	0.12	0.12	0.12	0.12	ns
T _{OUTJITTER}	MMCM Output Jitter ⁽⁵⁾	Note 3				
T _{OUTDUTY}	MMCM Output Clock Duty Cycle Precision ⁽⁶⁾	0.15	0.20	0.20	0.20	ns
T _{LOCKMAX}	MMCM Maximum Lock Time	100	100	100	100	μs
F _{OUTMAX}	MMCM Maximum Output Frequency	800	750	700	700	MHz
F _{OUTMIN}	MMCM Minimum Output Frequency ⁽⁷⁾⁽⁸⁾	4.69	4.69	4.69	4.69	MHz
T _{EXTFDVAR}	External Clock Feedback Variation	< 20% of clock input period or 1 ns Max				

Virtex-6 Device Pin-to-Pin Output Parameter Guidelines

All devices are 100% functionally tested. The representative values for typical pin locations and normal clock loading are listed in [Table 65](#). Values are expressed in nanoseconds unless otherwise noted.

Table 65: Global Clock Input to Output Delay Without MMCM

Symbol	Description	Device	Speed Grade				Units
			-3	-2	-1	-1L	
LVCMOS25 Global Clock Input to Output Delay using Output Flip-Flop, 12mA, Fast Slew Rate, <i>without</i> MMCM.							
TICKOF	Global Clock input and OUTFF <i>without</i> MMCM	XC6VLX75T	4.91	5.32	5.88	6.02	ns
		XC6VLX130T	4.89	5.33	6.00	6.13	ns
		XC6VLX195T	5.02	5.46	6.13	6.27	ns
		XC6VLX240T	5.02	5.46	6.13	6.27	ns
		XC6VLX365T	5.30	5.75	6.43	6.37	ns
		XC6VLX550T	N/A	6.02	6.72	6.60	ns
		XC6VLX760	N/A	6.26	6.97	6.87	ns
		XC6VSX315T	5.40	5.85	6.54	6.49	ns
		XC6VSX475T	N/A	6.01	6.71	6.61	ns
		XC6VHX250T	5.18	5.63	6.30	N/A	ns
		XC6VHX255T	5.20	5.66	6.34	N/A	ns
		XC6VHX380T	5.38	5.84	6.53	N/A	ns
		XC6VHX565T	N/A	6.03	6.71	N/A	ns
		XQ6VLX130T	N/A	5.33	6.00	6.13	ns
		XQ6VLX240T	N/A	5.46	6.13	6.27	ns
		XQ6VLX550T	N/A	N/A	6.72	6.60	ns
		XQ6VSX315T	N/A	5.85	6.54	6.49	ns
		XQ6VSX475T	N/A	N/A	6.71	6.61	ns

Notes:

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.

Virtex-6 Device Pin-to-Pin Input Parameter Guidelines

All devices are 100% functionally tested. The representative values for typical pin locations and normal clock loading are listed in [Table 68](#). Values are expressed in nanoseconds unless otherwise noted.

Table 68: Global Clock Input Setup and Hold Without MMCM

Symbol	Description	Device	Speed Grade				Units
			-3	-2	-1	-1L	
Input Setup and Hold Time Relative to Global Clock Input Signal for LVCMS25 Standard.⁽¹⁾							
T _{PSFD} / T _{PHFD}	Full Delay (Legacy Delay or Default Delay) Global Clock Input and IFF ⁽²⁾ without MMCM	XC6VLX75T	1.33/ 0.03	1.44/ 0.03	1.75/ 0.03	2.18/ -0.22	ns
		XC6VLX130T	1.31/ -0.08	1.54/ -0.08	1.88/ -0.08	2.31/ -0.12	ns
		XC6VLX195T	1.36/ -0.11	1.60/ -0.11	1.97/ -0.11	2.40/ -0.25	ns
		XC6VLX240T	1.36/ -0.11	1.60/ -0.11	1.97/ -0.11	2.40/ -0.25	ns
		XC6VLX365T	1.79/ -0.28	1.87/ -0.28	2.17/ -0.28	2.48/ -0.24	ns
		XC6VLX550T	N/A	2.22/ -0.12	2.36/ -0.12	2.77/ -0.26	ns
		XC6VLX760	N/A	2.19/ -0.24	2.35/ -0.24	2.71/ -0.21	ns
		XC6VSX315T	1.75/ -0.09	1.85/ -0.09	2.06/ -0.09	2.47/ -0.24	ns
		XC6VSX475T	N/A	2.14/ -0.14	2.31/ -0.14	2.71/ -0.30	ns
		XC6VHX250T	1.93/ -0.22	2.04/ -0.22	2.25/ -0.22	N/A	ns
		XC6VHX255T	1.81/ -0.33	2.11/ -0.33	2.56/ -0.33	N/A	ns
		XC6VHX380T	1.93/ -0.11	2.04/ -0.11	2.25/ -0.11	N/A	ns
		XC6VHX565T	N/A	2.20/ -0.12	2.39/ -0.12	N/A	ns
		XQ6VLX130T	N/A	1.54/ -0.08	1.88/ -0.08	2.31/ -0.12	ns
		XQ6VLX240T	N/A	1.60/ -0.11	1.97/ -0.11	2.40/ -0.25	ns
		XQ6VLX550T	N/A	N/A	2.36/ -0.12	2.77/ -0.26	ns
		XQ6VSX315T	N/A	1.85/ -0.09	2.06/ -0.09	2.47/ -0.24	ns
		XQ6VSX475T	N/A	N/A	2.31/ -0.14	2.71/ -0.30	ns

Notes:

- Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage.
- IFF = Input Flip-Flop or Latch
- A Zero "0" Hold Time listing indicates no hold time or a negative hold time. Negative values can not be guaranteed "best-case", but if a "0" is listed, there is no positive hold time.

Table 70: Clock-Capable Clock Input Setup and Hold With MMCM

Symbol	Description	Device	Speed Grade				Units
			-3	-2	-1	-1L	
Input Setup and Hold Time Relative to Clock-capable Clock Input Signal for LVCMS25 Standard.⁽¹⁾							
T _{PSMMC} /T _{PHMMC}	No Delay Clock-capable Clock Input and IFF ⁽²⁾ with MMCM	XC6VLX75T	1.56/ -0.25	1.69/ -0.25	1.86/ -0.25	1.91/ -0.15	ns
		XC6VLX130T	1.64/ -0.25	1.78/ -0.25	1.95/ -0.25	2.00/ -0.14	ns
		XC6VLX195T	1.65/ -0.24	1.79/ -0.24	1.96/ -0.24	2.01/ -0.15	ns
		XC6VLX240T	1.65/ -0.24	1.79/ -0.24	1.96/ -0.24	2.01/ -0.15	ns
		XC6VLX365T	1.66/ -0.25	1.79/ -0.25	1.97/ -0.25	2.02/ -0.15	ns
		XC6VLX550T	N/A	1.97/ -0.24	2.16/ -0.24	2.19/ -0.14	ns
		XC6VLX760	N/A	2.39/ -0.20	2.63/ -0.20	2.21/ -0.10	ns
		XC6VSX315T	1.67/ -0.25	1.80/ -0.25	1.98/ -0.25	2.03/ -0.16	ns
		XC6VSX475T	N/A	1.98/ -0.29	2.17/ -0.29	2.21/ -0.20	ns
		XC6VHX250T	1.63/ -0.24	1.76/ -0.24	1.94/ -0.24	N/A	ns
		XC6VHX255T	1.63/ -0.19	1.76/ -0.19	1.99/ -0.19	N/A	ns
		XC6VHX380T	1.80/ -0.23	1.94/ -0.23	2.13/ -0.23	N/A	ns
		XC6VHX565T	N/A	1.94/ -0.08	2.13/ -0.08	N/A	ns
		XQ6VLX130T	N/A	1.78/ -0.25	1.95/ -0.25	2.00/ -0.14	ns
		XQ6VLX240T	N/A	1.79/ -0.24	1.96/ -0.24	2.01/ -0.15	ns
		XQ6VLX550T	N/A	N/A	2.16/ -0.24	2.19/ -0.14	ns
		XQ6VSX315T	N/A	1.80/ -0.25	1.98/ -0.25	2.03/ -0.16	ns
		XQ6VSX475T	N/A	N/A	2.17/ -0.29	2.21/ -0.20	ns

Notes:

1. Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage.
2. IFF = Input Flip-Flop or Latch
3. Use IBIS to determine any duty-cycle distortion incurred using various standards.

Table 72: Package Skew

Symbol	Description	Device	Package	Value	Units
TPKGSKW	Package Skew ⁽¹⁾	XC6VLX75T	FF484	95	ps
			FF784	146	ps
		XC6VLX130T	FF484	95	ps
			FF784	146	ps
			FF1156	165	ps
			XC6VLX195T	FF784	145
		FF1156		182	ps
		XC6VLX240T		FF784	146
			FF1156	182	ps
			FF1759	187	ps
		XC6VLX365T	FF1156	189	ps
			FF1759	184	ps
		XC6VLX550T	FF1759	196	ps
			FF1760	249	ps
		XC6VLX760	FF1760	236	ps
		XC6VSX315T	FF1156	168	ps
			FF1759	190	ps
		XC6VSX475T	FF1156	168	ps
			FF1759	204	ps
		XC6VHX250T	FF1154	166	ps
		XC6VHX255T	FF1155	168	ps
			FF1923	228	ps
		XC6VHX380T	FF1154	159	ps
			FF1155	172	ps
			FF1923	227	ps
			FF1924	220	ps
		XC6VHX565T	FF1923	232	ps
			FF1924	197	ps
XQ6VLX130T	RF784	146	ps		
	RF1156	165	ps		
	FFG1156	165	ps		
XQ6VLX240T	RF784	146	ps		
	RF1156	182	ps		
	FFG1156	182	ps		
	RF1759	187	ps		
XQ6VLX550T	RF1759	196	ps		
XQ6VSX315T	RF1156	168	ps		
	FFG1156	168	ps		
	RF1759	190	ps		
XQ6VSX475T	RF1156	168	ps		
	FFG1156	168	ps		
	RF1759	204	ps		

Notes:

- These values represent the worst-case skew between any two SelectIO resources in the package: shortest flight time to longest flight time from Pad to Ball (7.0 ps per mm).
- Package trace length information is available for these device/package combinations. This information can be used to deskew the package.

Date	Version	Description of Revisions
01/18/10	2.1	Changed absolute maximum ratings for both V_{IN} and V_{TS} in Table 1 . Added data to Table 3 . Added data to Table 5 . Updated SSTL15 in Table 7 . Updated V_{OCM} and V_{OD} values in Table 8 . Added eFUSE endurance Table 12 . Added values to $V_{MGTREFCLK}$ and V_{IN} in Table 13, page 11 . Added values and updated tables in the GTX Transceiver Specifications and GTH Transceiver Specifications sections. Added Table 27 and Figure 4 . Revised parameters and values in Table 39 . Updated Table 40, page 23 . Added data to Table 41 . Updated speed specification to v1.04 with appropriate changes to Table 42 and Table 43 including production release of the XC6VLX240T for -1 and -2 speed grades. Speed specification changes and numerous updates also made to Table 44 , and Table 49 through Table 71 . Added data to Table 73 and Table 74 .
02/09/10	2.2	Revised description of C_{IN} in Table 3 . Clarified values in Table 5 . Fixed SDR LVDS unit error in Table 41 .
04/12/10	2.3	Added note 3 and update value of n in Table 3 . Clarified simultaneous power-down in Power-On Power Supply Requirements . Updated external reference junction temperatures in Table 40, Analog-to-Digital Specifications . Updated speed specification to v1.05 with appropriate changes to Table 42 and Table 43 including production release of the XC6VLX130T for -1 and -2 speed grades. Fixed note 4 in Table 48 . Increased the -2 specification for $F_{IDELAYCTRL_REF}$ and clarified units for $T_{IDELAYPAT_JIT}$ in Table 53 . Added note 1 to Table 62 .
05/11/10	2.4	Updated F_{RXREC} in Table 22 . Revised $F_{IDELAYCTRL_REF}$ in Table 53 . Removed $T_{RCKO_PARITY_ECC}$: Clock CLK to ECCPARITY in standard ECC mode row in Table 57 . Added XC6VLX130T values to Table 72 .
05/26/10	2.5	Added XC6VLX195T data to Table 5 . Updated values in Table 22 including adding note 2 and note 3. Updated speed specification to v1.06 with appropriate changes to Table 42 and Table 43 including production release of the XC6VLX195T for -1 and -2 speed grades. Added XC6VLX195T values to Table 72 .
07/16/10	2.6	Changed Table 42 and Table 43 to production status on the -3 speed grade XC6VLX130T, XC6VLX195T, and XC6VLX240T devices. Added XC6VHX250T data to Table 4 and Table 72 . Added Note 6 to Table 64 .
07/23/10	2.7	Changed Table 42 and Table 43 to production status on the XC6VLX75T, XC6VLX365T, XC6VLX550T, XC6VLX760, XC6VSX315T, and XC6VSX475T devices using ISE 12.2 software with speed specification v1.08. Updated $V_{CMOUTDC}$ equation to $MGTAVTT - D_{VPPOUT}/4$ in Table 17 . Updated some -3, -2, -1 specifications in Table 65 through Table 72 . Added and updated -1L specifications to Table 41 and for most switching characteristics tables.
07/30/10	2.8	Changed Table 42 and Table 43 to production status on the -1L speed grade for the XC6VLX130T, XC6VLX195T, XC6VLX240T, XC6VLX365T, and XC6VLX550T devices using ISE 12.2 software with current speed specifications. Also updated the speed specifications for XC6VLX75T, XC6VLX550T, and XC6VSX315T. Updated V_{CCINT} specifications for -1L speed grade industrial temperature range devices in Table 2 .
09/20/10	2.9	In Table 32 , changed $F_{GPLLMAX}$ specification in -3 column from 5.951 to 5.591. In Table 40 , changed F_{MAX} for the DCLK from 250 MHz to 80 MHz.
10/18/10	2.10	The specification change in version 2.9, Table 40 is described in XCN10032, Virtex-6 FPGA: GTX Transceiver User Guide, Family Data Sheet (SYSMON DCLK), and JTAG ID Changes . In this version (2.10), -1L(I) data is added to Table 4 and clarified in Note 2. Changed Table 42 and Table 43 to production status on the -1L speed grade XC6VLX75T, XC6VLX760, XC6VSX315T, and XC6VSX475T devices using ISE 12.3 software with current speed specifications. Revised the XC6VLX760 -1L speed specification for $T_{PHMMCMB}$ in Table 69 and $T_{PHMMCMB}$ in Table 70 .
01/17/11	2.11	Changed in Table 42 and Table 43 to production status on the XC6VHX250T devices using ISE 12.4 software with current speed specifications. Added industrial temperature range (T_i) recommended specifications to Table 2 ; including specific ranges for the -2I XC6VSX475T, XC6VLX550T, XC6VLX760, and XC6VHX565T devices. Added note 3 to Table 36 and maximum total jitter values. Added note 4 to Table 37 and maximum sinusoidal jitter values. Added note 2 to Table 43 . Revised F_{MAX} descriptions in Table 57 and added note 12. Added note 8 to F_{PFDMIN} in Table 64 . The following revisions are due to specification changes as described in XCN11009, Virtex-6 FPGA: Data Sheet, User Guides, and JTAG ID Updates . In Table 59: Configuration Switching Characteristics, page 49 , revised -1L specifications for T_{POR} , F_{MCCK} , $F_{MCCKTOL}$, $T_{SMCSCCK}$, $T_{SMCCCKW}$, F_{RBCK} , F_{TCK} , F_{TCKB} , T_{MCCKL} , and T_{MCCKH} . In Table 64: MMCM Specification , added bandwidth settings to F_{PFDMIN} and added note 1.

Date	Version	Description of Revisions
02/08/11	2.12	Removed note 1 from Table 4 as the larger devices (XC6VLX550T, XC6VLX760, XC6VSX475T, and XC6VHX565T) are now offered in -2L. Updated Table 4 and Table 5 with data for the XC6VHX380T in the FF(G)1154 package. In Table 41 , updated -1L specification for DDR3. Added Note 1 to Table 42 . Moved the XC6VHX380T devices in the FF(G)1154 package to production release in Table 43 using ISE 12.4 software with current speed specifications. Updated description for F_{INDUTY} in Table 64 .
02/25/11	3.0	Designated the data sheet as Preliminary for all devices not already labeled production in Table 42 . Changed the XC6VHX380T devices in all packages to production status in Table 42 and Table 43 . Removed note 1 from Table 42 . Added maximum specifications to Table 25 . Updated $T_{HAVCC2HAVCCRX}$ in Table 27 . Updated the typical values and notes in Table 28 and Table 29 . Added values to Table 30 and Table 31 . In Table 34 , added values for T_{LOCK} and T_{PHASE} . Updated the values in Table 36 and added note 3. Updated Table 37 and added note 4.
03/21/11	3.1	Updated Table 2 including Note 7 . In Table 4 , added Note 3 and -2E, extended temperature range to the XC6VLX550T, XC6VLX760, XC6VSX475T, and XC6VHX380T devices, and added Note 5 for the XC6VHX565T. Updated Table 28 typical values. Updated the description for $F_{IDELAYCTRL_REF}$ in Table 53 . Updated F_{MCCK} in Table 59 .
04/01/11	3.2	Added T_j values for C, E, and I temperature ranges to Table 2 . Updated the I_{CCQ} values in Table 4 . Updated F_{GCLK} in Table 34 . Designated the data sheet as Production for all devices not already labeled production in Table 42 . Changed the XC6VHX255T and XC6VHX565T devices in all packages to production status in Table 42 and Table 43 . This included updates to the Virtex-6 Device Pin-to-Pin Output Parameter Guidelines and Virtex-6 Device Pin-to-Pin Input Parameter Guidelines for these devices. Production speed specifications for these devices are available using the speed specification v1.14 in the ISE 13.1 software update. Updated and added package skew values to Table 72 ; these values are correct with regards to previous production released speed specifications in software. Updated copyright page 1 and Notice of Disclaimer .
12/08/11	3.3	Production release of the Defense-grade XQ devices in Table 42 and Table 43 using ISE v13.3 v1.17 Patch for -2 and -1 speed specifications; and v1.10 for -1L speed specifications. Added the XQ6VLX130T, XQ6VLX240T, XQ6VLX550T, XQ6VSX315T, and XQ6VSX475T to the data sheet which included adding Table 45 . Updated T_j in Table 2 . In Table 40 , updated T_j for most specifications and added Note 4 . Added Note 4 to Table 41 . Added -1(XQ) speed specification columns only to Table 50 , Table 51 , Table 52 , and Table 58 . Updated V_{OD} in Table 8 , V_{OCM} in Table 9 , and V_{OCM} and V_{DIFF} in Table 10 . Updated the Power-On Power Supply Requirements section. In Table 27 , updated maximum specification for $T_{HAVCC2HAVCCRX}$ and added Note 3 . Updated T_j in Table 40 . In Table 41 , increased the DDR LVDS receiver (SPI-4.2) -1 speed grade performance value from 1.0 Gb/s to 1.1 Gb/s. In Table 60 , updated the F_{MAX} to add a separate row for the LX760 device values. The speed specifications in the software tools have always matched these values for the LX760, the data sheet is now correct. Updated the notes for $T_{OUTJITTER}$ in Table 64 .
01/12/12	3.4	Added the temperature range -2E to Note 5 in Table 4 .

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